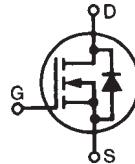


# TrenchT2™ Power MOSFET

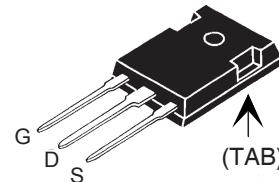
## IXTH420N04T2

N-Channel Enhancement Mode  
Avalanche Rated  
Fast Intrinsic Diode

**V<sub>DSS</sub>** = 40V  
**I<sub>D25</sub>** = 420A  
**R<sub>DS(on)</sub>** ≤ 2.0mΩ



TO-247



G = Gate      D = Drain  
S = Source      TAB = Drain

Symbol	Test Conditions	Maximum Ratings	
V <sub>DSS</sub>	T <sub>J</sub> = 25°C to 175°C	40	V
V <sub>DGR</sub>	T <sub>J</sub> = 25°C to 175°C, R <sub>GS</sub> = 1MΩ	40	V
V <sub>GSM</sub>	Transient	±20	V
I <sub>D25</sub>	T <sub>C</sub> = 25°C (Chip Capability)	420	A
I <sub>LRMS</sub>	Lead Current Limit, RMS	160	A
I <sub>DM</sub>	T <sub>C</sub> = 25°C, Pulse Width Limited by T <sub>JM</sub>	1050	A
I <sub>A</sub>	T <sub>C</sub> = 25°C	200	A
E <sub>AS</sub>	T <sub>C</sub> = 25°C	960	mJ
P <sub>D</sub>	T <sub>C</sub> = 25°C	935	W
T <sub>J</sub>		-55 ... +175	°C
T <sub>JM</sub>		175	°C
T <sub>stg</sub>		-55 ... +175	°C
T <sub>L</sub>	1.6mm (0.062in.) from Case for 10s	300	°C
T <sub>sold</sub>	Plastic Body for 10 seconds	260	°C
M <sub>d</sub>	Mounting Torque	1.13 / 10	Nm/lb.in.
Weight		6	g

Symbol	Test Conditions (T <sub>J</sub> = 25°C Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
BV <sub>DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	40		V
V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.5		3.5 V
I <sub>GSS</sub>	V <sub>GS</sub> = ± 20V, V <sub>DS</sub> = 0V			±200 nA
I <sub>DSS</sub>	V <sub>DS</sub> = V <sub>DSS</sub> , V <sub>GS</sub> = 0V			10 μA
	T <sub>J</sub> = 150°C			300 μA
R <sub>DS(on)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 100A, Note 1	1.6	2.0	mΩ

### Features

- International Standard Package
- 175°C Operating Temperature
- High Current Handling Capability
- Avalanche Rated
- Fast Intrinsic Diode
- Low R<sub>DS(on)</sub>

### Advantages

- Easy to Mount
- Space Savings
- High Power Density

### Applications

- DC/DC Converters and Off-line UPS
- Primary- Side Switch
- High Current Switching Applications

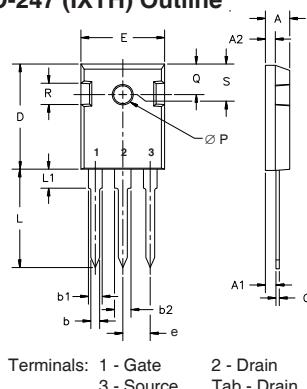
Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
$g_{fs}$	$V_{DS} = 10\text{V}$ , $I_D = 60\text{A}$ , Note 1	70	120	S
$C_{iss}$ $C_{oss}$ $C_{rss}$	$V_{GS} = 0\text{V}$ , $V_{DS} = 25\text{V}$ , $f = 1\text{MHz}$	19.7	nF	
		3220	pF	
		690	pF	
$R_{GI}$	Gate Input Resistance	1.45	$\Omega$	
$t_{d(on)}$ $t_r$ $t_{d(off)}$ $t_f$	<b>Resistive Switching Times</b> $V_{GS} = 10\text{V}$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_D = 100\text{A}$ $R_G = 2\Omega$ (External)	23	ns	
		27	ns	
		70	ns	
		155	ns	
$Q_{g(on)}$ $Q_{gs}$ $Q_{gd}$	$V_{GS} = 10\text{V}$ , $V_{DS} = 0.5 \cdot V_{DSS}$ , $I_D = 0.5 \cdot I_{D25}$	315	nC	
		68	nC	
		73	nC	
$R_{thJC}$			0.16	$^\circ\text{C}/\text{W}$
$R_{thCH}$		0.21		$^\circ\text{C}/\text{W}$

#### Source-Drain Diode

Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Specified)	Characteristic Values		
		Min.	Typ.	Max.
$I_s$	$V_{GS} = 0\text{V}$		420	A
$I_{SM}$	Repetitive, Pulse Width Limited by $T_{JM}$		1680	A
$V_{SD}$	$I_F = 100\text{A}$ , $V_{GS} = 0\text{V}$ , Note 1		1.3	V
$t_{rr}$ $I_{RM}$ $Q_{RM}$	$I_F = 150\text{A}$ , $V_{GS} = 0\text{V}$ -di/dt = $100\text{A}/\mu\text{s}$ $V_R = 20\text{V}$	74	ns	
		2.7	A	
		100	nC	

Note 1. Pulse test,  $t \leq 300\mu\text{s}$ ; duty cycle,  $d \leq 2\%$ .

TO-247 (IXTH) Outline



Terminals: 1 - Gate  
2 - Drain Tab - Drain  
3 - Source

Dim.	Millimeter Min. Max.	Inches Min. Max.
A	4.7 5.3	.185 .209
A <sub>1</sub>	2.2 2.54	.087 .102
A <sub>2</sub>	2.2 2.6	.059 .098
b	1.0 1.4	.040 .055
b <sub>1</sub>	1.65 2.13	.065 .084
b <sub>2</sub>	2.87 3.12	.113 .123
C	.4 .8	.016 .031
D	20.80 21.46	.819 .845
E	15.75 16.26	.610 .640
e	5.20 5.72	0.205 0.225
L	19.81 20.32	.780 .800
L1	4.50	.177
$\emptyset P$	3.55 3.65	.140 .144
Q	5.89 6.40	0.232 0.252
R	4.32 5.49	.170 .216
S	6.15 BSC 242 BSC	242 BSC

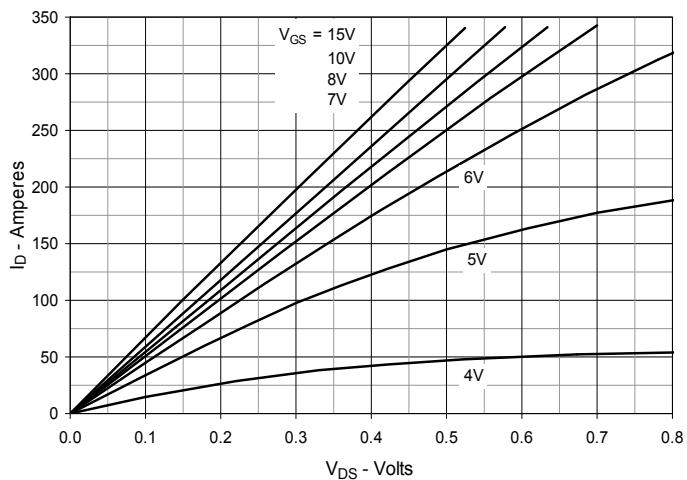
#### ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

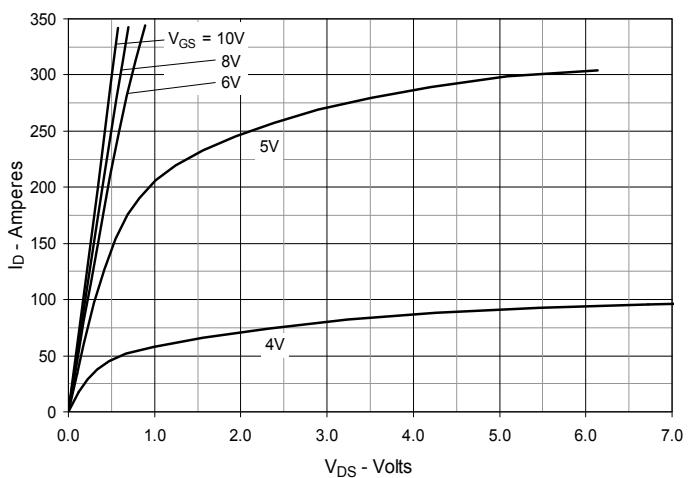
IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents: 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585 7,005,734 B2 7,157,338B2 4,850,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343 6,710,405 B2 6,759,692 7,063,975 B2 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505 6,710,463 6,771,478 B2 7,071,537

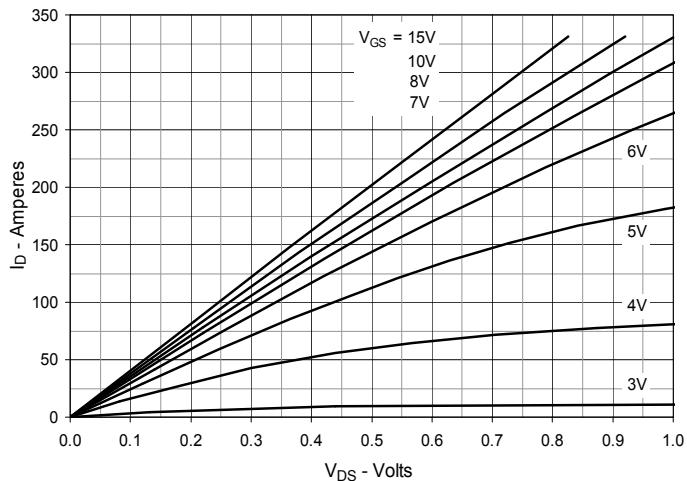
**Fig. 1. Output Characteristics  
@ 25°C**



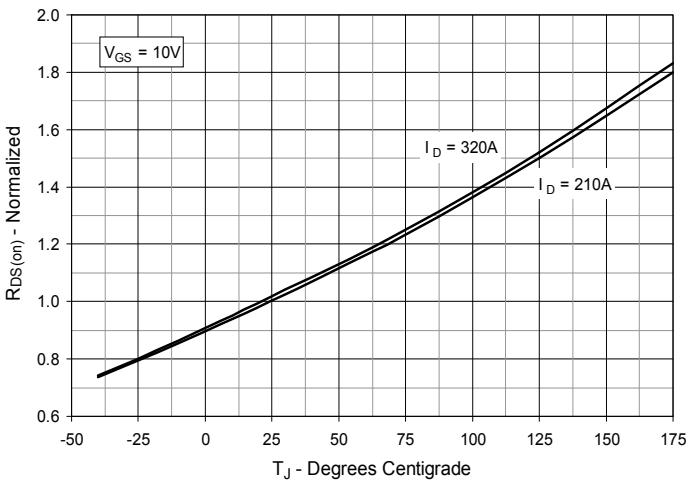
**Fig. 2. Extended Output Characteristics  
@ 25°C**



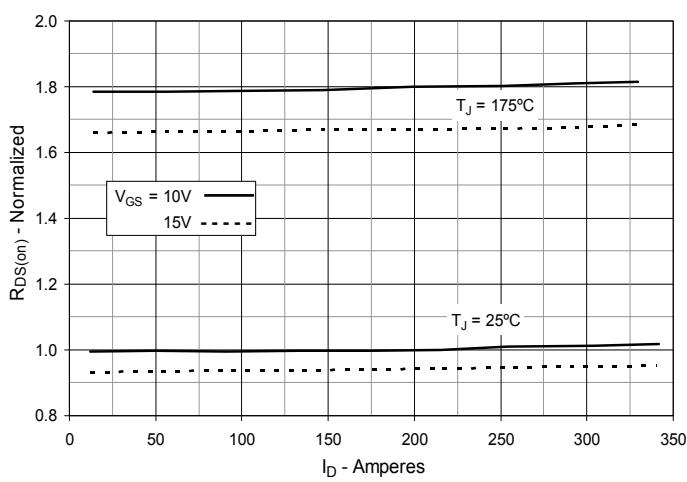
**Fig. 3. Output Characteristics  
@ 150°C**



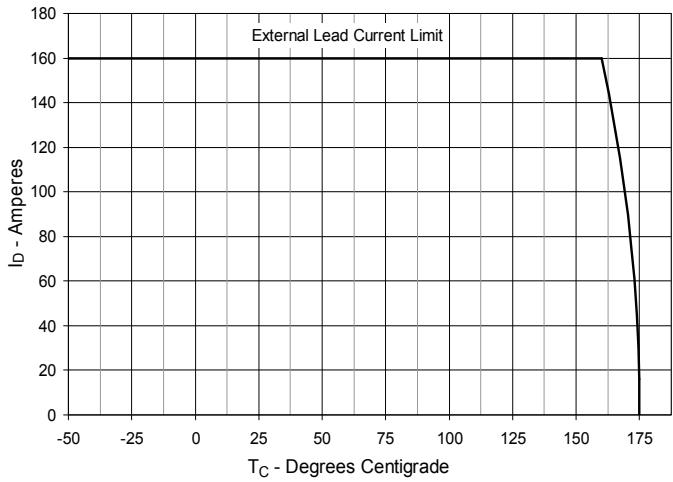
**Fig. 4.  $R_{DS(on)}$  Normalized to  $I_D = 210A$  Value vs.  
Junction Temperature**

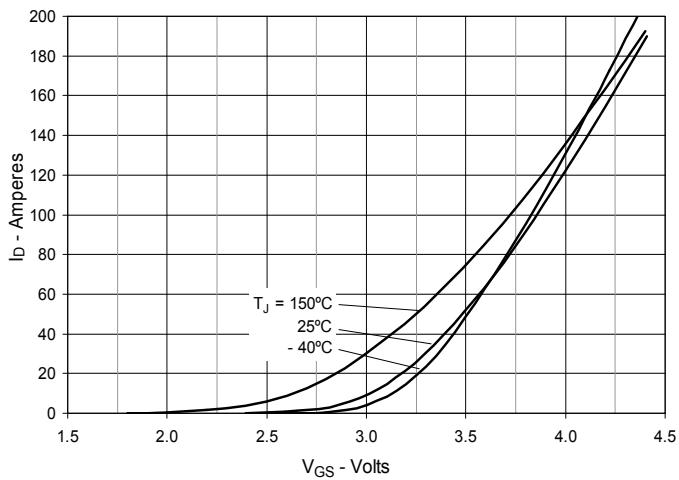
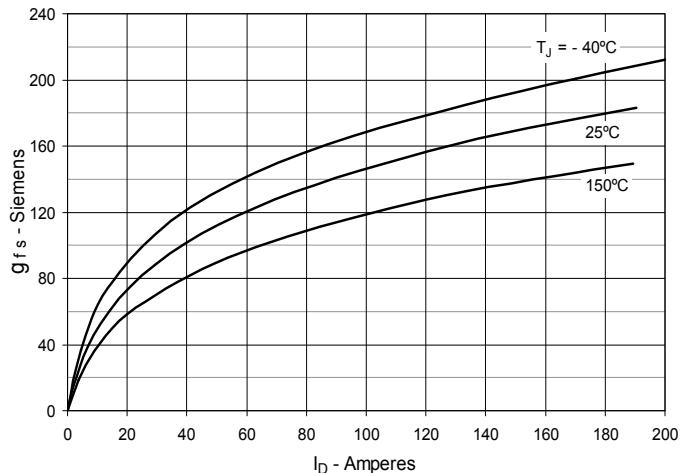
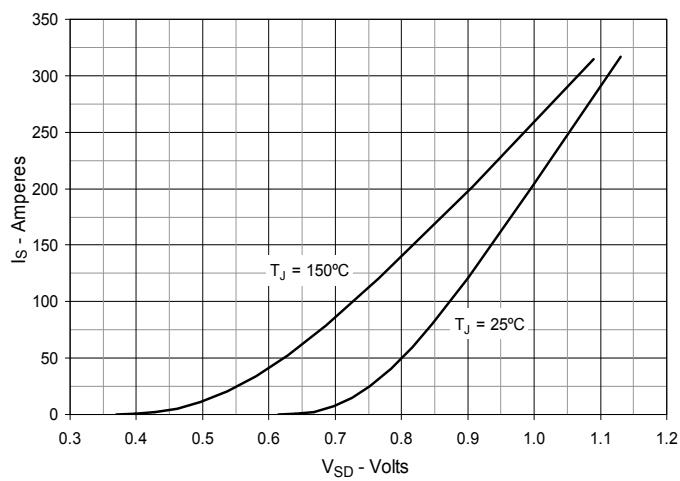
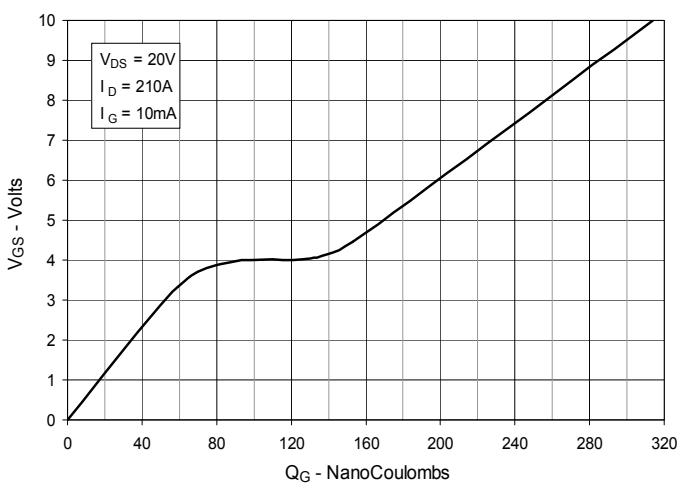
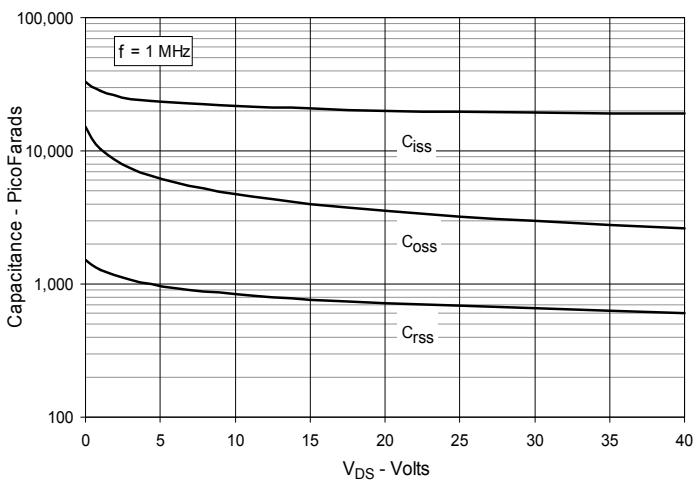
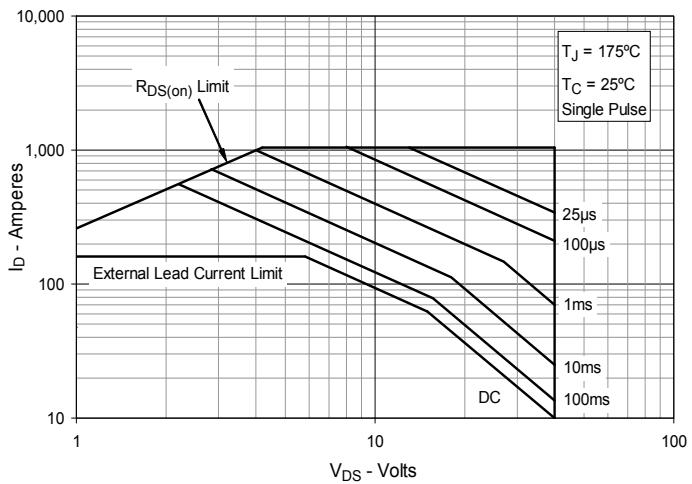


**Fig. 5.  $R_{DS(on)}$  Normalized to  $I_D = 210A$  Value vs.  
Drain Current**

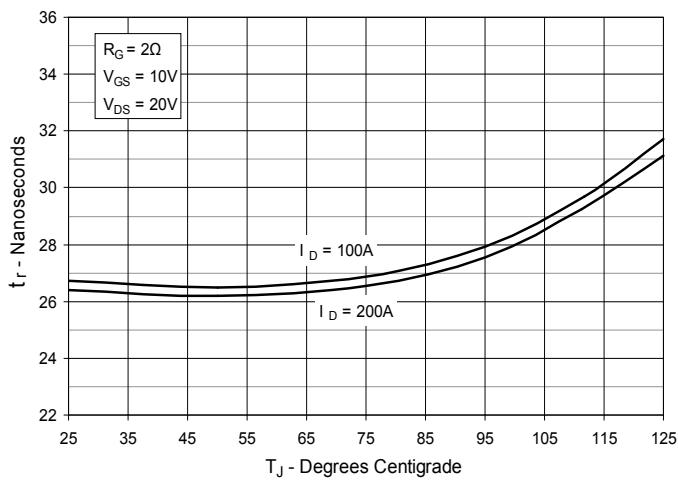


**Fig. 6. Drain Current vs. Case Temperature**

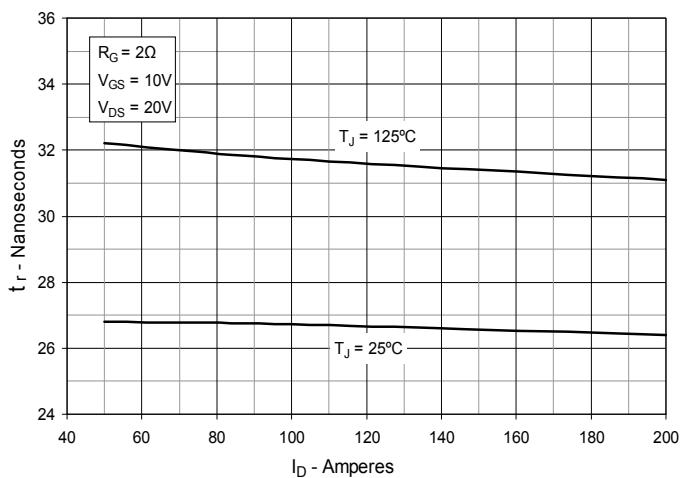


**Fig. 7. Input Admittance****Fig. 8. Transconductance****Fig. 9. Forward Voltage Drop of Intrinsic Diode****Fig. 10. Gate Charge****Fig. 11. Capacitance****Fig. 12. Forward-Bias Safe Operating Area**

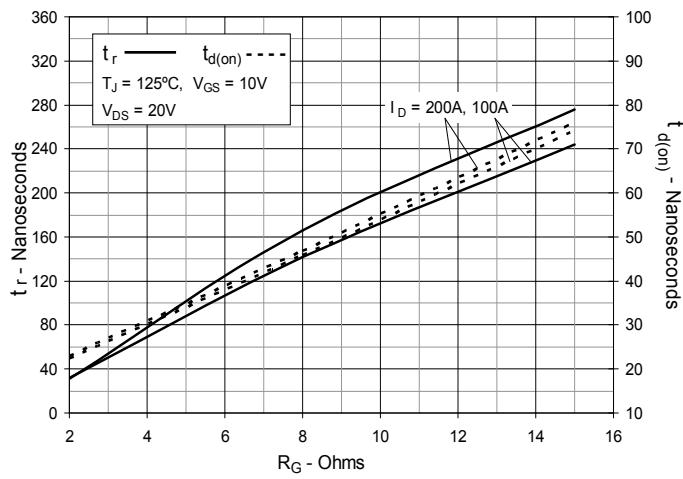
**Fig. 13. Resistive Turn-on  
Rise Time vs. Junction Temperature**



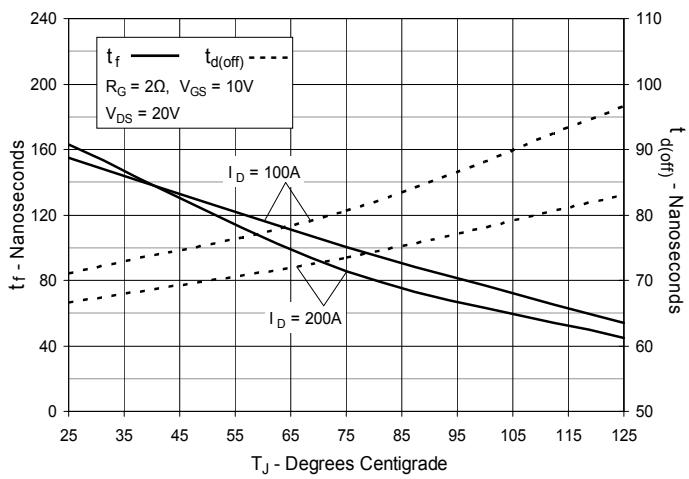
**Fig. 14. Resistive Turn-on  
Rise Time vs. Drain Current**



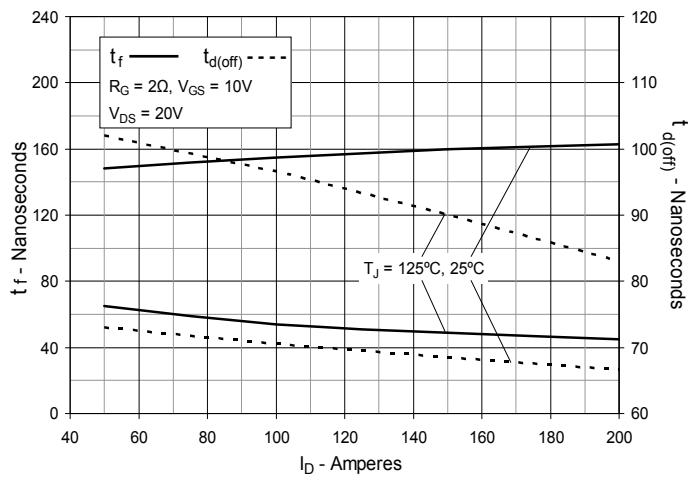
**Fig. 15. Resistive Turn-on  
Switching Times vs. Gate Resistance**



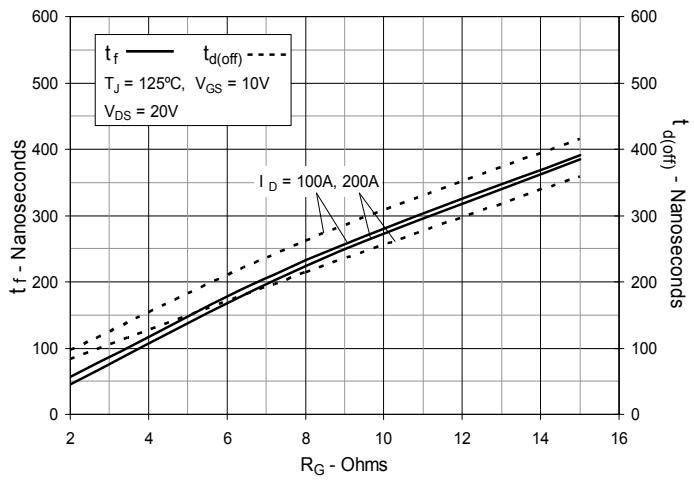
**Fig. 16. Resistive Turn-off  
Switching Times vs. Junction Temperature**



**Fig. 17. Resistive Turn-off  
Switching Times vs. Drain Current**



**Fig. 18. Resistive Turn-off  
Switching Times vs. Gate Resistance**



**Fig. 19. Maximum Transient Thermal Impedance**